## Chemical vapour-deposited silicon nitride

#### Part 4 Hardness characteristics

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The Vickers microhardness (VMH) of amorphous and crystalline chemical vapour-deposited silicon nitride (Pyrolytic-Si $_3$  N $_4$ ) prepared under various deposition conditions using SiCl $_4$ , NH $_3$  and H $_2$  has been measured at room temperature. The apparent VMH of Py–Si $_3$  N $_4$  increases with decreasing indenter load, following the Meyer equation. For the amorphous Py–Si $_3$  N $_4$ , the VMH value at a load of 100 g ranges from 2200 to 3200 kg mm $^{-2}$  depending upon deposition temperature ( $T_{\rm dep}$ ) and total gas pressure ( $P_{\rm tot}$ ). On the other hand, the VMH of the crystalline Py–Si $_3$  N $_4$  does not depend upon  $T_{\rm dep}$  and  $P_{\rm tot}$  but is affected by the preferred orientation. The hardness of the deposition surfaces with the (1 1 0), (2 1 0) and (2 2 2) orientations is 3800 kg mm $^{-2}$ , while that of the cross-section with the (0 0 1) orientation is 3100 kg mm $^{-2}$ . The hardness of the crystalline Py–Si $_3$  N $_4$  is also affected by the grain size. For the fine grained Py–Si $_3$  N $_4$  (about 1  $\mu$ m), the VMH varies from 4600 to 5000 kg mm $^{-2}$ . The hardnesses of three types of Py–Si $_3$  N $_4$  are discussed in comparison with those of other ceramics.

#### 1. Introduction

In high-temperature engineering applications, silicon nitride  $(Si_3N_4)$  has superior properties such as low coefficient of expansion, high strength, good chemical stability and low coefficient of friction. These applications include dies for resistance sintering, ball bearings, components in high-temperature gas turbine engines and inert components in corrosive environments [1-4].

Products of  $Si_3N_4$  are usually fabricated by reaction-sintering and hot-pressing techniques and thereby voids and some additives must be involved. Mechanical properties of the  $Si_3N_4$  products depend strongly upon the purity, porosity and microstructure in a way similar to other ceramics [4-10].

One of the most important properties required for high-temperature structural materials is the high degree of surface hardness that results in good abrasion and erosion resistance. However, the hardness values of  $\mathrm{Si}_3\mathrm{N}_4$  reported in the literature vary widely with the preparation techniques and conditions [4,8–20]. The Vickers microhard-

ness (VMH) at an applied load of 100 g is reported to be 1020 to  $2200\,\mathrm{kg\,mm^{-2}}$  for the reaction-sintered  $\mathrm{Si_3\,N_4}$  [9, 13] and 1600 to 3800 kg mm<sup>-2</sup> for the hot-pressed  $\mathrm{Si_3\,N_4}$  [4, 16].

Pyrolytic Si<sub>3</sub>N<sub>4</sub> obtained by a chemical vapour deposition technique is expected to possess excellent properties as compared with the reaction-sintered and hot-pressed Si<sub>3</sub>N<sub>4</sub>. Nevertheless, there are very few systematic investigations on the mechanical properties of Py-Si<sub>3</sub>N<sub>4</sub>. In making an assessment of Py-Si<sub>3</sub>N<sub>4</sub> for many potential applications, it is important to know its hardness characteristics. The only published value available for comparison is that of Kuntz et al. [19, 20] for Py-Si<sub>3</sub>N<sub>4</sub>, 2850 kg mm<sup>-2</sup> at an undefined load.

As reported previously [21-23], the massive amorphous and crystalline  $Py-Si_3N_4$  with thicknesses up to 4.6 mm have successfully been prepared in our laboratory, and the relations of the preparation conditions to the microstructure, density, deposition rate and crystal structure have been investigated. In the present work we report on the VMH values of  $Py-Si_3N_4$  measured at

TABLE I Some properties of amorphous and crystalline Py-Si<sub>3</sub> N<sub>4</sub>

	Amorphous Py-Si <sub>3</sub> N <sub>4</sub>	Crystalline Py-Si <sub>3</sub> N <sub>4</sub>
Structure	Amorphous	α (hexagonal)
Colour	White (translucent)	White to black (translucent)
Density (g cm <sup>-3</sup> )	2.60 to 2.89 (82 to 91% of $D_{th}^*$ )	3.15 to 3.18 (99 to 100% of $D_{th}^*$ )
Maximum deposition rate (mm h <sup>-1</sup> )	0.36	0.73
Preferred orientation	_	(1 1 0), (2 1 0), (2 2 2)
Oxygen content (wt %)	2.2 to 1.6	1.1 to 0.3
Grain size (µm)		
(in C region)†		> 10
(in A-C boundary)†	_	~ 1

<sup>\*</sup> $D_{\rm th}$ : a theoretical density of  $\alpha$ -Si<sub>3</sub> N<sub>4</sub>, 3.18 g cm<sup>-3</sup>.

room temperature and the effects of the microstructure, density and crystal orientation on the hardness.

#### 2. Experimental procedure

#### 2.1. Py-Si<sub>3</sub> N<sub>4</sub> samples

The amorphous and crystalline  $Py-Si_3N_4$  were deposited on a graphite substrate, using a mixture of  $NH_3$ ,  $SiCl_4$  and  $H_2$ . The preparation conditions were as follows: flow rates of  $NH_3$ ,  $SiCl_4$  (in liq.) and  $H_2 = 60,0.8$  and  $700 \, \mathrm{cm}^3 \, \mathrm{min}^{-1}$ , respectively, deposition temperature ( $T_{\rm dep}$ ) = 1100 to 1500° C and total gas pressure ( $P_{\rm tot}$ ) = 10 to 80 Torr. The procedure for the sample preparation has been reported in detail in a previous report [21]. Some properties of  $Py-Si_3N_4$  used in the present experiment are summarized in Table I. Fig. 1 shows the relationship between the structure of  $Py-Si_3N_4$  and the preparation conditions,  $T_{\rm dep}$  and  $P_{\rm tot}$  [21].

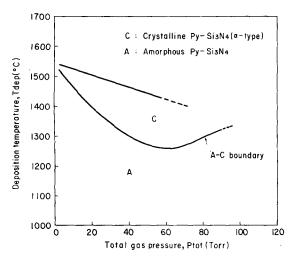


Figure 1 Effect of deposition temperature  $(T_{dep})$  and total gas pressure  $(P_{tot})$  on the structure of  $Py-Si_3N_4$ .

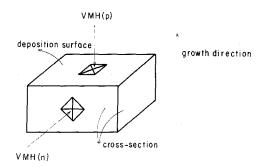


Figure 2 Two kinds of the indentations;  $VMH_{(p)}$  and  $VMH_{(n)}$  are the hardness values parallel and perpendicular to the growth direction, respectively.

#### 2.2. VMH measurements

The Py-Si<sub>3</sub>N<sub>4</sub> samples formed were mounted in resin, cut parallel and perpendicular to the deposition surface and polished with various grades of diamond paste to obtain a mirror-like surface for the measurements. As shown in Fig. 2, the VMH measurements of the deposition surface  $(VMH_{(p)})$ and the cross-section (VMH(n)) were made using an AKASHI diamond Vickers hardness tester (Model: MVK, Type: D, apex angle: 136°) equipped with an optical microscope (x 400). Further detailed observations of indentation diagonals were performed at a higher magnification of  $\sim$  x 3000 when necessary. Readings were successfully achieved by the use of polarized light and differential interference conditions. The indenterloads of 25 to 300 g were applied for 30 sec and the relationship between the hardness and the load was determined. Almost all measurements were carried out using a load of 100 g. The VMH values reported in this work are the average of at least 20 indentations.

<sup>†</sup> See Fig. 1.

## 2.3. Relationship between VMH and the indenter load

In microhardness testing, VMH is given by the relationship:

$$VMH = 1854.4 Pd^{-2} (kg mm^{-2})$$
 (1)

where P is the load in g and d the length of the diagonal in  $\mu$ m. The relationship between P and d can be expressed empirically by the Meyer equation:

$$P = ad^n (2)$$

where a and n are constants depending upon the materials [24]. Thus, if the  $\log P$  is plotted versus the  $\log d$ , the Meyer exponent n is obtained from the slope of a straight line. A relationship between VMH and P can be obtained from Equations 1 and 2 as follows:

$$VMH = 1854.4 \, ad^{n-2} \, (kg \, mm^{-2}) \tag{3}$$

Thus, VMH is independent of the load only when n = 2, while VMH increases and decreases with decreasing load when n < 2 and n > 2, respectively.

#### 3. Results

#### 3.1. Variation of VMH with indenter load

Fig. 3 shows the variation of VMH with the load for the amorphous  $Py-Si_3N_4$  with the lowest hardness which was prepared at  $T_{\rm dep}=1100^{\circ}$  C and  $P_{\rm tot}=40\,{\rm Torr}$ . It is shown that the VMH values at loads of 300 and 25 g, VMH<sub>300</sub> and VMH<sub>25</sub>, are 2000 and 2400 kg mm<sup>-2</sup>, respectively. On the other hand, as shown in Fig. 4, VMH<sub>300</sub> = 3200 kg mm<sup>-2</sup> and VMH<sub>25</sub> = 6400 kg mm<sup>-2</sup> were obtained for the crystalline  $Py-Si_3N_4$  with the highest hardness prepared at  $T_{\rm dep}=1400^{\circ}$  C and  $P_{\rm tot}=20\,{\rm Torr}$ . In both cases, VMH increases with decreasing load, according to the Meyer equation (Equation 2). Similar load dependence of VMH

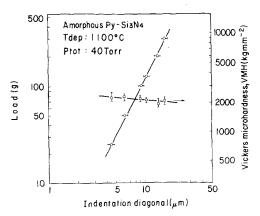


Figure 3 Relationship between Vickers microhardness and indenter load for amorphous Py-Si<sub>3</sub> N<sub>4</sub> prepared at  $T_{\rm dep}$  = 1100° C and  $P_{\rm tot}$  = 40 Torr.

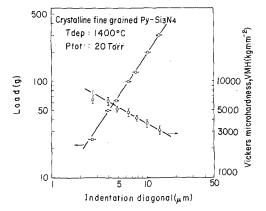


Figure 4 Relationship between Vickers microhardness and indenter load for fine grained crystalline Py-Si<sub>3</sub>N<sub>4</sub> prepared at  $T_{\rm dep}=1400^{\circ}$  C and  $P_{\rm tot}=20$  Torr.

was observed in all the  $Py-Si_3N_4$  samples. The load dependence is affected by the intrinsic hardness of each sample, as seen in Figs. 3 and 4. The values for the Meyer exponent n tend to decrease with increasing VMH, as summarized in Table II.

TABLE II	Values of	of the	Meyer	exponent	of	Py-	-Si <sub>3</sub> N	٧ <sub>4</sub>
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Preparation conditions		Crystal	Vickers microhardness,	Meyer	
T <sub>dep</sub> (° C)	P <sub>tot</sub> (Torr)	structure*	VMH <sub>100</sub> (kg mm <sup>-2</sup> )	exponent, n	
1100	40	A	2200	1.92	
1200	10	A	3200	1.72	
1200	40	Α	2300	1.90	
1300	10	$\mathbf{A}^{\circ}$	3100	1.75	
1400	20	A	2500	1.69	
1300	60	C	3800 (p) <sup>†</sup>	1.68	
1300	60	C	3100 (n)†	1.70	
1400	20	C	4800	1.54	

<sup>\*</sup> A, amorphous; C, crystalline (α-Si, N, ).

<sup>†</sup> p and n are the hardness parallel and perpendicular to the growth direction, respectively (see Fig. 2).

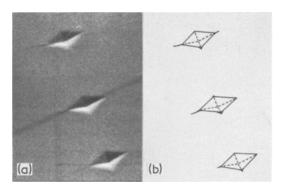


Figure 5 Scanning electron micrograph, taken in a direction at an angle of  $60^{\circ}$  from the direction of electron beam, of microhardness indentations at a  $100 \, \mathrm{g}$  load for the crystalline Py-Si<sub>3</sub>N<sub>4</sub> prepared at  $T_{\rm dep} = 1300^{\circ} \, \mathrm{C}$  and  $P_{\rm tot} = 60 \, \mathrm{Torr}$ . (a) original, (b) sketched; diagonal  $\sim 7.0 \, \mu \mathrm{m}$ .

Fig. 5 shows a scanning electron micrograph of indentations at 100 g load taken by inclining the surface to be observed at an angle of 60° to the direction of electron beam for the crystalline Py—Si<sub>3</sub>N<sub>4</sub> prepared at 1300° C and 60 Torr. As outlined schematically in the sketch of Fig. 5b, the star-like cracks radiated from the corners of indentations. These cracks appear more predominantly at higher loads in the hard samples. Sometimes, edges of indentations were spalled out at high loads of 200 and 300 g.

# 3.2. The hardness of the deposition surface and the cross-section, $VMH_{(p)}$ and $VMH_{(p)}$

Hardness measurements were carried out on two kinds of surfaces, the deposition surface and the cross-section, as shown in Fig. 2. Fig. 6 shows the VMH<sub>100,p</sub> and VMH<sub>100,n</sub> values for the amorphous Py-Si<sub>3</sub>N<sub>4</sub> prepared at  $T_{dep} = 1300^{\circ}$  C and  $P_{tot} =$ 30 Torr and the crystalline Py-Si<sub>3</sub> N<sub>4</sub> deposited at 1300° C and 60 Torr and at 1400° C and 40 Torr. The VMH<sub>100,n</sub> values are independent of the distance from the substrate-side surface, exept that the region in contact with the substrate (below 0.1 mm) in the crystalline Py-Si<sub>3</sub>N<sub>4</sub> formed at 1400° C and 40 Torr, shows a decrease in hardness as indicated by  $\triangle$  in the figure. This means that the present samples are almost homogeneous. For the crystalline Py-Si<sub>3</sub>N<sub>4</sub>, VMH<sub>100,p</sub> is approximately 600 kg mm<sup>-2</sup> higher than VMH<sub>100,n</sub> as marked ▲ and . However, there is a negligible difference in value between VMH<sub>100,n</sub> and VMH<sub>100,p</sub> for the amorphous Py-Si<sub>3</sub> N<sub>4</sub>.

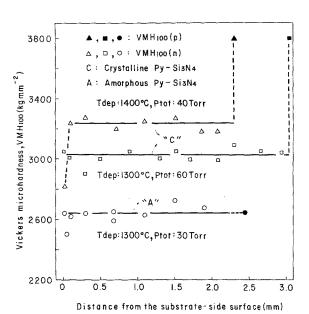


Figure 6 The Vickers microhardness on the deposition surface (VMH<sub>100</sub>,p) and the cross-section (VMH<sub>100</sub>,n) for Py-Si<sub>3</sub>N<sub>4</sub> prepared at  $T_{\rm dep}=1400^{\circ}$  C and  $P_{\rm tot}=40$  Torr,  $T_{\rm dep}=1300^{\circ}$  C and  $P_{\rm tot}=60$  Torr, and  $T_{\rm dep}=1300^{\circ}$  C and  $P_{\rm tot}=30$  Torr. p and n, see Fig. 2.

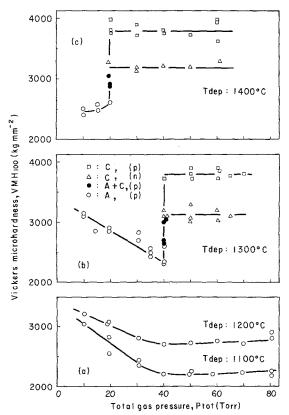


Figure 7 Effect of total gas pressure  $(P_{tot})$  on Vickers microhardness  $(VMH_{100})$ . A, amorphous; C, crystalline  $(\alpha - Si_3 N_4)$ ; p and n, see Fig. 2.

#### 3.3. Effect of total gas pressure on VMH

Fig. 7 represents the relationship between VMH<sub>100</sub> and Ptot for the Py-Si<sub>3</sub>N<sub>4</sub> samples prepared at  $T_{\rm dep}$  of 1100 to 1400° C. In the case of the amorphous Py-Si<sub>3</sub>N<sub>4</sub>, only VMH<sub>100,n</sub> is plotted in Fig. 7 because of the almost identical values of  $VMH_{100,p}$  and  $VMH_{100,n}$ . The  $VMH_{100,p}$  of the amorphous Py-Si<sub>3</sub> N<sub>4</sub> decreases with increasing  $P_{\text{tot}}$  in the range of 10 to 40 Torr as indicated by o in Fig. 7a and b. The maximum and minimum VMH<sub>100 p</sub> values of the amorphous Py-Si<sub>3</sub>N<sub>4</sub> were 3050 and 2200 kg mm<sup>-2</sup> at 1100° C, 3200 and 2700 kg mm<sup>-2</sup> at 1200° C and 3100 and 2300 kg mm<sup>-2</sup> at 1300° C, respectively. VMH<sub>100,p</sub> varies widely at 1300° C and 40 Torr (Fig. 7b) and at 1400° C and 20 Torr (Fig. 7c) corresponding to the A-C boundary condition (Fig. 1). This is the result of partial heterogeneous depositions of the amorphous and crystalline Py-Si<sub>3</sub> N<sub>4</sub> by fluctuations in the preparation conditions during the deposition [21]. Although the data are not included in Fig. 7, the small grained portion (about 1 µm grain size) of the crystalline Py-Si<sub>3</sub>N<sub>4</sub> produced in the A-C boundary region indicates high VMH<sub>100,FG</sub> values of 4600 to 5000 kg mm<sup>-2</sup>, while the VMH<sub>100</sub> values of the large grained portion (about  $10 \,\mu\text{m}$ ) are  $VMH_{(p)} =$  $3800 \text{ kg mm}^{-2} \text{ and VMH}_{(n)} = 3100 \text{ kg mm}^{-2}$ .

The hardness of the crystalline Py-Si<sub>3</sub>N<sub>4</sub> at  $1300^{\circ}$  C and above 40 Torr is independent of  $P_{\text{tot}}$ ; VMH<sub>100,p</sub> = 3800 kg mm<sup>-2</sup> and VMH<sub>100,n</sub> = 3100 kg mm<sup>-2</sup> as shown in Fig. 7b. The variation of VMH<sub>100</sub> with  $P_{\text{tot}}$  for the crystalline deposits at  $1400^{\circ}$  C and above 20 Torr is analogous to that at  $1300^{\circ}$  C, being VMH<sub>100,p</sub> =  $3800 \text{ kg mm}^{-2}$  and VMH<sub>100,n</sub> =  $3200 \text{ kg mm}^{-2}$ .

### 3.4. Effect of deposition temperature on VMH

The relation between VMH<sub>100</sub> and  $T_{\rm dep}$  is given in Fig. 8. For the amorphous Py-Si<sub>3</sub>N<sub>4</sub>, VMH<sub>100,p</sub> is particularly influenced by  $T_{\rm dep}$ , as indicated by the curves a to e. The maximum VMH<sub>100,p</sub> appeared at  $T_{\rm dep}$  1200° C. In the case of the crystalline Py-Si<sub>3</sub>N<sub>4</sub>, different VMH<sub>100</sub> versus  $T_{\rm dep}$  relations exist for the samples designated by n, p and FG and are independent of  $P_{\rm tot}$  as indicated by curves i, j and k; the values of VMH<sub>100,p</sub>, VMH<sub>100,p</sub> and VMH<sub>100,FG</sub> are 3150, 3800 and 4800 kg mm<sup>-2</sup>, respectively. Curves f, g and h were drawn from the results obtained at the A-C boundary.

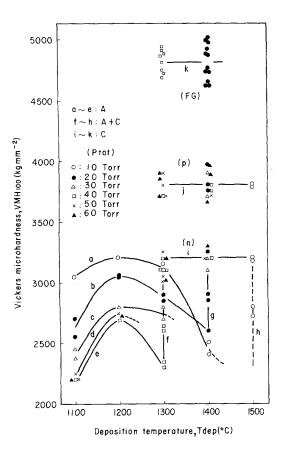


Figure 8 Effect of deposition temperature  $(T_{dep})$  on Vickers microhardness (VMH<sub>100</sub>). A, amorphous; C, crystalline  $(\alpha-Si_3N_4)$ ; FG, fine grained; p and n, see Fig. 2.

#### 3.5. Effect of density on VMH

Values of VMH<sub>100</sub> are plotted as a function of density in Fig. 9. VMH<sub>100,p</sub> of the amorphous Py—Si<sub>3</sub>N<sub>4</sub> deposited at  $T_{dep}$  of 1100 and 1200° C increases with density ( $\blacktriangle$ ,  $\triangle$ ), whereas VMH<sub>100,p</sub> at 1300 and 1400° C varies markedly in spite of the constant density ( $\bigcirc$ ,  $\square$ ) [22]. This shows that the density dependence of the hardness is affected by  $T_{dep}$ . For the crystalline Py—Si<sub>3</sub>N<sub>4</sub>, the density was very close to the theoretical value (3.18 g cm<sup>-3</sup>) and was independent of the preparation conditions [22]. Three kinds of VMH<sub>100,p</sub>, i.e. VMH<sub>100,p</sub>, VMH<sub>100,p</sub> and VMH<sub>100,FG</sub>, are independent of the density.

#### 4. Discussion

## 4.1. Instrumental and reading errors in VMH measurements

Because of the indenter load dependence of VMH, the use of a standard load is essential when comparing hardness values. For the Py-Si<sub>3</sub>N<sub>4</sub> sample with the highest hardness shown in Fig. 4,

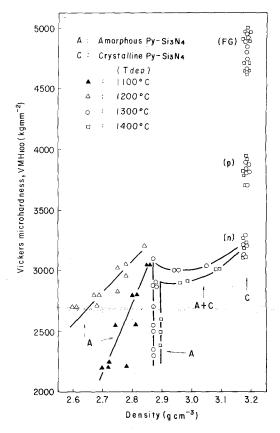


Figure 9 Effect of density on Vickers microhardness (VMH<sub>100</sub>). FG, fine grained; p and n, see Fig. 2.

the loads below 50 g give rise to small diagonals, e.g.  $4 \mu m$  at 50 g and  $2.7 \mu m$  at 25 g. In the case of such small microhardness impressions, it is difficult to make detailed microscopic observations of the diagonals. As an alternative means, the diagonals were measured by enlarging the negatives of the micrographs (× 3000). At higher loads above 125 g, fractured (or spalled) indentations were obtained on the much harder samples. Almost all indentations on the crystalline Py—Si<sub>3</sub>N<sub>4</sub> showed slightly fractured shapes, in which small cracks

were generated at the corners of indentations as indicated in Fig. 5b. In consideration of the errors resulting from small indentations and crack formation, a load of 100 g was chosen as a standard load in the present VMH measurements. Moreover, since the present Py—Si<sub>3</sub> N<sub>4</sub> samples are translucent, particular attention was directed to the conditions of optical microscopy, such as focusing and the intensity of radiation. The experimental error in measurements of the VMH values under the present experimental conditions was within  $\pm \,6\%$ .

In order to attain accurate visual and instrumental observations, the hardness measurements of boron and  $TiC_{0.88}$  were carried out under the same indentation conditions. These results are shown in Table III together with data from the literature [25–29]. The measured hardness values are in good agreement with the referenced ones.

# 4.2. The indenter load dependence of VMH The hardness of ceramics generally depends upon the load in such a manner that it apparently increases with decreasing load. The relation between VMH and the load for various kinds of Si<sub>3</sub>N<sub>4</sub> is shown in Fig. 10.

Pratt [9] reported n = 1.48 and 1.38 for the reaction-sintered  $\alpha$ - and  $\beta$ -Si<sub>3</sub>N<sub>4</sub>, respectively. Noakes and Pratt [13] and Thompson and Pratt [10] reported that n of the reaction-sintered Si<sub>3</sub>N<sub>4</sub> containing both the  $\alpha$ - and  $\beta$ -phases was 1.4. Coe et al. [4] measured VMH of the hotpressed Si<sub>3</sub>N<sub>4</sub> with 1 wt% of MgO in the range of 100 to 1000 g and found that VMH decreased with increasing load. In this work the VMH values of Py—Si<sub>3</sub>N<sub>4</sub> depended strongly upon the load, with the Meyer exponent n of the order of 1.54 to 1.92, and the load dependence of VMH became more pronounced in the samples with higher VMH as given in Table II. The values of n for Py—Si<sub>3</sub>N<sub>4</sub>

TABLE III The hardness of boron and titanium carbide

Material	Hardness (kg mm <sup>-2</sup> )	V or K*	Load (g)	Reference
В	3400	V	50	25
В	2800	V	100	26
TiC	2988	V	30	25
TiC	2200, 2700	K	100	27
TiC <sub>0.73-0.94</sub>	2060 to 2800	V	1000	28
TiC <sub>0.96</sub>	2600	V, K	500	29
В	2760 ± 200	V	100	This work
TiC <sub>0.88</sub>	2690 ± 160	V	100	This work

<sup>\*</sup> V, Vickers microhardness; K, Knoop microhardness.

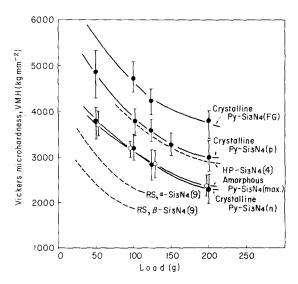


Figure 10 The load dependence of Vickers microhardness (VMH) for various kinds of  $Si_3N_4$ . RS, reaction-sintered; HP, hot-pressed; FG, fine grained; p and n, see Fig. 2.

are larger than those for the impure  $Si_3N_4$  such as reaction-sintered and hot-pressed products.

The values of the Meyer exponent n for the transition metal oxides were reported by Wood and Hodgkiess [30] as follows:  $TiO_2$  (1.72),  $Ta_2O_3$  (1.85),  $Nb_2O_5$  (1.48),  $Cu_2O$  (2.06), NiO (1.71), FeO (1.85 to 1.87),  $Fe_3O_4$  (1.51 to 1.95), CoO (1.91),  $Cr_2O_3$  (1.5 to 1.93) and ZnO (1.80 to 1.87). The load dependence of VMH is also observed in the case of hard refractory materials such as  $B_4C$ , ZrC,  $TiB_2$ ,  $Al_2O_3$ , WC and SiC [9, 24]. In particular, the VMH values of WC and SiC varied markedly with load; the Meyer exponents n are 1.16 and 1.18 for WC and SiC, respectively [9].

#### 4.3. VMH of amorphous Py-Si<sub>3</sub> N<sub>4</sub>

Bean et al. [31] measured the Knoop microhardness at a very low load of 8 g (KMH<sub>8</sub>) and Mohs' hardness of the thin amorphous  $Py-Si_3N_4$  films  $1\,\mu$ m thick prepared by pyrolysis of a  $SiH_4+NH_3+H_2$  system. They reported that KMH<sub>8</sub> was dependent upon the NH<sub>3</sub> concentration of the gas mixture. At  $0.6\%\,NH_3$ , the amorphous  $Py-Si_3N_4$  exhibited a maximum hardness, KMH<sub>8</sub> = 3500 kg mm<sup>-2</sup>, which can possibly be converted to VMH<sub>100</sub> = 2400 kg mm<sup>-2</sup> by reference to the present load dependence of VMH and by using the empirical relations between VMH and KMH. They also reported that the Mohs' hardness increased with increasing  $T_{\rm dep}$  up to 900° C, but independent of  $T_{\rm dep}$  at 900 to 1200° C.

In the present work, the VMH<sub>100</sub> value for the amorphous Py-Si<sub>3</sub>N<sub>4</sub> was remarkably affected by the preparation conditions, especially  $T_{\text{dep}}$  and  $P_{\text{tot}}$ , and varied between 2200 and 3200 kg mm<sup>-2</sup> (see Figs. 7 and 8). As shown in Fig. 9, the relationship between VMH<sub>100</sub> and density differs depending upon  $T_{\text{dep}}$ . Yajima et al. [32] investigated the VMH values of pyrolytic graphite and siliconated pyrolytic graphite, and demonstrated that the VMH value is strongly influenced by the crosslinks existing between the crystallites. In the present experiments, it appears that the VMH value of the amorphous Py-Si<sub>3</sub> N<sub>4</sub> is affected by a structure which resembles that of cross-links. The nature of the growing cone of the amorphous Py-Si<sub>3</sub> N<sub>4</sub> varied with  $P_{\text{tot}}$  [21], which seems to be related to the hardness (Fig. 7).

## 4.4. Effect of preferred orientations on VMH

As shown in Figs. 6 to 8, VMH<sub>100,p</sub> of the crystalline Py-Si<sub>3</sub>N<sub>4</sub> was higher than VMH<sub>100,n</sub>. As reported in Part 3 [23], it was observed that the crystalline Py-Si<sub>3</sub> N<sub>4</sub> exhibited the marked (1 1 0), (210) and (222) orientations, and that the orientations varied from (110) and (210) to (222) with decreasing  $P_{tot}$  and with increasing deposition rate [23]. However, VMH<sub>100,p</sub> and  $VMH_{100,n}$  were independent of  $T_{dep}$  and  $P_{tot}$ . From these facts, it is considered that the hardness of the (2 1 0) and (1 1 0) planes of  $\alpha$ -Si<sub>3</sub>N<sub>4</sub> are not different from that of the (222) plane, and that the difference between VMH<sub>(p)</sub> and VMH<sub>(n)</sub> is due to the presence of the (001) plane. Actually, the hardness of the (001) plane is lower than that of the (110) and (100) planes for  $\alpha$ -Si<sub>3</sub>N<sub>4</sub> single crystals prepared in our laboratory [33].

#### 4.5 Effect of grain size on VMH

The relations between the hardness and the average grain size are represented by the Hall-Petch equation for grain-boundary hardening and the Cottrell equation for anti-phase boundary hardening [5-7,34], respectively:

$$H = H_0 + K_{\rm H} L^{-1/2} \tag{4}$$

$$H = H_0 + K_C L^{-1} (5)$$

where H is the hardness,  $H_0$ ,  $K_H$  and  $K_C$  are experimental constants and L is the grain size.

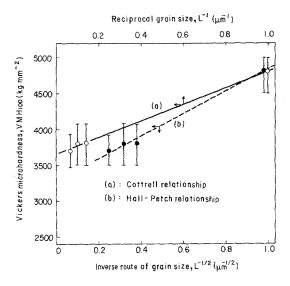


Figure 11 Effect of grain size on Vickers microhardness (VMH<sub>100</sub>) for crystalline Py-Si<sub>3</sub>N<sub>4</sub>.

Fig. 11 shows the relationships between VMH<sub>100</sub> (p and FG) of the crystalline Py-Si<sub>3</sub>N<sub>4</sub> and the inverse square root ( $L^{-1/2}$ ) and the inverse ( $L^{-1}$ ) of grain size. In either case, the linear relationships are observed within experimental error. It is difficult to determine which model is better, because of the lower accuracy in the measurement of the grain size. For Equation 5, however, the extrapolation of the values to  $L^{-1} = 0$  gives  $H_0 = 3650$  kg mm<sup>-2</sup> which is close to the hardness (VMH<sub>100</sub> = 3600 kg mm<sup>-2</sup>) of the (100) and (110) planes of  $\alpha$ -Si<sub>3</sub>N<sub>4</sub> single crystals [34].

Coe et al. [4] measured VMH of the theoretically dense and fine grained (0.3 to 0.6  $\mu$ m) Si<sub>3</sub>N<sub>4</sub> containing both  $\alpha$ - and  $\beta$ -phases obtained by hot-

pressing the  $\alpha$ -Si<sub>3</sub>N<sub>4</sub> powder with 1 wt % MgO. They reported that VMH<sub>100</sub> was 3700 kg mm<sup>-2</sup> and that the hardness increased with decreasing grain size. Although the grain size of the hotpressed Si<sub>3</sub>N<sub>4</sub> is smaller than that of Py-Si<sub>3</sub>N<sub>4</sub> in the present work, VMH of the hot-pressed Si<sub>3</sub>N<sub>4</sub> is lower than that of Py-Si<sub>3</sub>N<sub>4</sub>. This may be attributed to the vitreous phase (MgSiO<sub>3</sub>) formed in the grain boundaries of the hot-pressed Si<sub>3</sub>N<sub>4</sub> [35].

## 4.6. Comparisons of VMH between Py—Si<sub>3</sub>N<sub>4</sub> and other refractory materials

The hardness values of  $Si_3N_4$  prepared by various techniques are summarized in Table IV. The data listed are limited to the hardness measured at a load of  $100 \, \mathrm{g}$ ,  $VMH_{100}$  and  $KMH_{100}$ , except for the hardness of  $Py-Si_3N_4$ . The hardness values reported in the literature are widely scattered, the cause of which seems to be fluctuations in purity, density, grain size, microstructure and crystal orientation of  $Si_3N_4$  with the methods of production.

In Fig. 12, the VMH of the present Py-Si<sub>3</sub>N<sub>4</sub> is compared with those of typical carbides, nitrides, borides and oxides [36-40]. As described above, the comparison of the hardness of different materials should be done at the same indenter load. Fig. 12 indicates that the present Py-Si<sub>3</sub>N<sub>4</sub> samples are harder than the well-known hard materials such as TiC, W<sub>2</sub>C, TiB<sub>2</sub> and Al<sub>2</sub>O<sub>3</sub>. Especially, the fine grained Py-Si<sub>3</sub>N<sub>4</sub> is superior in hardness to B<sub>4</sub>C.

TABLE IV Comparative hardness data on various kinds of Si<sub>3</sub> N<sub>4</sub>

Si <sub>3</sub> N <sub>4</sub> *	Phase and additive	Density† (g cm <sup>-3</sup> )	Orientation and grain size	$VMH_{100}$ and $KMH_{100}$ ‡ (kg mm <sup>-2</sup> )	Reference
RS	α	2.1	-	2200	[9]
RS	β	2.1	<del></del>	1700	[9]
RS	$\alpha + \beta + Si$	2.37 to 2.59	~	1020	[13]
HP	$\alpha + \beta$ , 5 wt % MgO	3.12 to 3.18	~-	1600 to 1800	[16]
HP	$\alpha + \beta$ , 1 wt % MgO	3.17 to 3.19	0.3 to 0.6 $\mu$ m	3700	[4]
HP	$\alpha + \beta$ , 2.5 at % Ce <sub>2</sub> O <sub>3</sub>	3.18 to 3.22	2 to 3 μm	2550 to 2600 (KMH)	[18]
Py	α	3.07 to 3.18	(2 2 2), (0 0 2)	2850 (unknown load)	[19, 20]
Py	Amorphous	-	- <u>-</u> -	3500 (8 g load, KMH)	[31]
Py	Amorphous	2.60 to 2.90	-	2200 to 3200	This work
Py (p) §	α	3.18	$(110), (210), (222) > 10\mu\text{m}$	3800	This work
Py (n) §	α	3.18	$(0.02)$ , $> 10 \mu\text{m}$	3100	This work
Py (FG) §	α	3.18	1 μm	4800	This work

<sup>\*</sup> RS, reaction-sintered; HP, hot-pressed; Py, chemical vapour-deposited (Pyrolytic).

The theoretical densities of  $\alpha$ -Si<sub>3</sub>N<sub>4</sub> and  $\beta$ -Si<sub>3</sub>N<sub>4</sub> are 3.18 and 3.19 g cm<sup>-3</sup>, respectively.

<sup>&</sup>lt;sup>‡</sup> VMH<sub>100</sub>, the Vickers microhardness; KMH<sub>100</sub>, the Knoop microhardness at 100 g load.

<sup>§</sup> p and n, parallel and perpendicular to the growth direction, respectively; FG, fine grained.

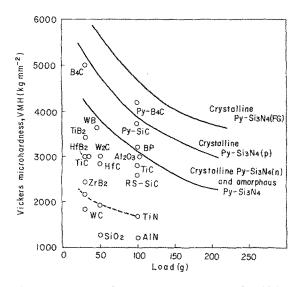


Figure 12 Comparative microhardness data on  $Py-Si_3N_4$  and hard refractory materials. FG, fine grained; p and n, see Fig. 2.

#### 5. Conclusions

- (1) The Vickers microhardness (VMH) of Py— $Si_3N_4$  increased with decreasing indenter load. The Meyer exponent n varied from 1.54 to 1.92 depending upon the intrinsic hardness of each sample, and tended to be smaller in the harder Py— $Si_3N_4$ .
- (2) For the amorphous  $Py-Si_3N_4$ , the hardness was dependent upon the preparation conditions of the deposition temperature  $(T_{dep})$  and the total gas pressure  $(P_{tot})$ . At  $T_{dep}$  of 1100 to 1300° C, the hardness decreased with increasing  $P_{tot}$  from 10 to 40 Torr. The maximum and minimum values of  $VMH_{100}$ , measured at a 100 g load, were 3200 kg mm<sup>-2</sup> at 1200° C and 10 Torr, and 2200 kg mm<sup>-2</sup> at 1100° C and 40 Torr, respectively. Moreover, the hardness of the amorphous  $Py-Si_3N_4$  was related to the density.
- (3) For the crystalline  $Py-Si_3N_4$  ( $\alpha$ -type), the hardness was independent of  $T_{dep}$  and  $P_{tot}$ , but it was affected by the preferred orientation. The VMH<sub>100,p</sub> value of the deposition surface with the (110), (210) and (222) orientations was 3800 kg mm<sup>-2</sup>, while the VMH<sub>100,n</sub> value of the cross-section with the (001) orientation was 3100 kg mm<sup>-2</sup>.
- (4) The hardness of the crystalline  $Py-Si_3N_4$  increased with decreasing grain size. For the fine grained (about  $1 \mu m$ )  $Py-Si_3N_4$  produced in the

amorphous—crystalline boundary region, the VMH<sub>100,FG</sub> values ranged from 4600 to 5000 kg mm<sup>-2</sup>.

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